

First Semester M.Tech. Degree Examination, Dec.2023/Jan.2024
Digital VLSI Design

Time: 3 hrs.

Max. Marks: 100

Note: 1. Answer any FIVE full questions, choosing ONE full question from each module.

2. *M*: Marks, *L*: Bloom's level, *C*: Course outcomes.

Module – 1			M	L	C
Q.1	a.	Explain the operation of MOS with external bias.	10	L1	CO1
	b.	Obtain the basic current-voltage characteristics of an n-channel MOSFET.	10	L2	CO1
OR					
Q.2	a.	Draw and explain the basic structure of the resistive – load inverter circuit.	6	L1	CO1
	b.	Write the equations of V_{OH} , V_{OL} and V_{IL} from the typical voltage transfer characteristics of resistive load inverter.	6	L2	CO1
	c.	Prove that depletion type nMOS transistor over come high stand by (DC) power dissipation when connected load.	8	L4	CO1
Module – 2					
Q.3	a.	Explain the circuit operation of CMOS inverter circuit.	12	L3	CO2
	b.	Find the value of τ_{fall} and τ_{rise} of a typical inverter.	8	L4	CO2
OR					
Q.4	a.	Calculate interconnect delay using i) RC Delay model ii) The Elmore delay.	10	L4	CO2
	b.	Write a note on switching power dissipation of CMOS inverters.	10	L6	CO2
Module – 3					
Q.5	a.	Summarize the characteristics of memory devices.	8	L1	CO3
	b.	Explain the four transistor DRAM cell with two storage nodes.	6	L2	CO3
	c.	Explain the circuit topology of the CMOS SRAM cell.	6	L5	CO3
OR					
Q.6	a.	Explain a three-transistor DRAM cell with the pull up and read/write circuitry.	10	L3	CO3
	b.	Draw and explain a 4-bit $\times$ 4-bit NAND based ROM array.	5	L5	CO3
	c.	Explain the hysteresis characteristics of a ferroelectric capacitor.	5	L1	CO3

1 of 2

Module – 4

Q.7	a.	Discuss the charge storage and charge leakage process in nMOS pass transistor.	10	L2	CO4
	b.	Implement the function $F = \overline{(A_1 A_2 A_3 + B_1 B_2)}$ using dynamic CMOS logic gate.	5	L4	CO4
	c.	Realize $Z = AB + (C + D)(E + F) + GH$ using standard CMOS logic.	5	L4	CO4

OR

Q.8	a.	Explain typical BiCMOS inverter circuit with four MOSFET and two BJT's.	6	L1	CO4
	b.	Explain the BiCMOS inverter circuit with i) Resistive base pull down ii) Active base pull down.	8	L3	CO4
	c.	Draw the circuit diagram of a BiCMOS NAND2 and NOR2 gate.	6	L4	CO4

Module – 5

Q.9	a.	Explain different models of ESD testing.	6	L5	CO5
	b.	Explain the design of tristable output circuit.	6	L6	CO5
	c.	Explain simple on-chip clock generation circuit using ring oscillator.	8	L6	CO5

OR

Q.10	a.	List and express the circuit parameter x_i occurring during manufacturing process and operating conditions.	10	L6	CO5
	b.	Explain the performance modeling procedure.	10	L1	CO5

* * * * *